

**METHOD FOR CLASSIFYING DEFECTS AND
DEVICE FOR THE SAME**

ABSTRACT OF THE DISCLOSURE

A method for classifying defects includes imaging an inspected object. An image of a defect candidate is extracted from an image obtained by said imaging step. Said extracted defect candidate image is classified into a first category. Said extracted defect candidate image is classified into a second category. Said extracted defect candidate image and information relating to said classification into said first category and information relating to said classification into said second category are displayed on a screen.

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